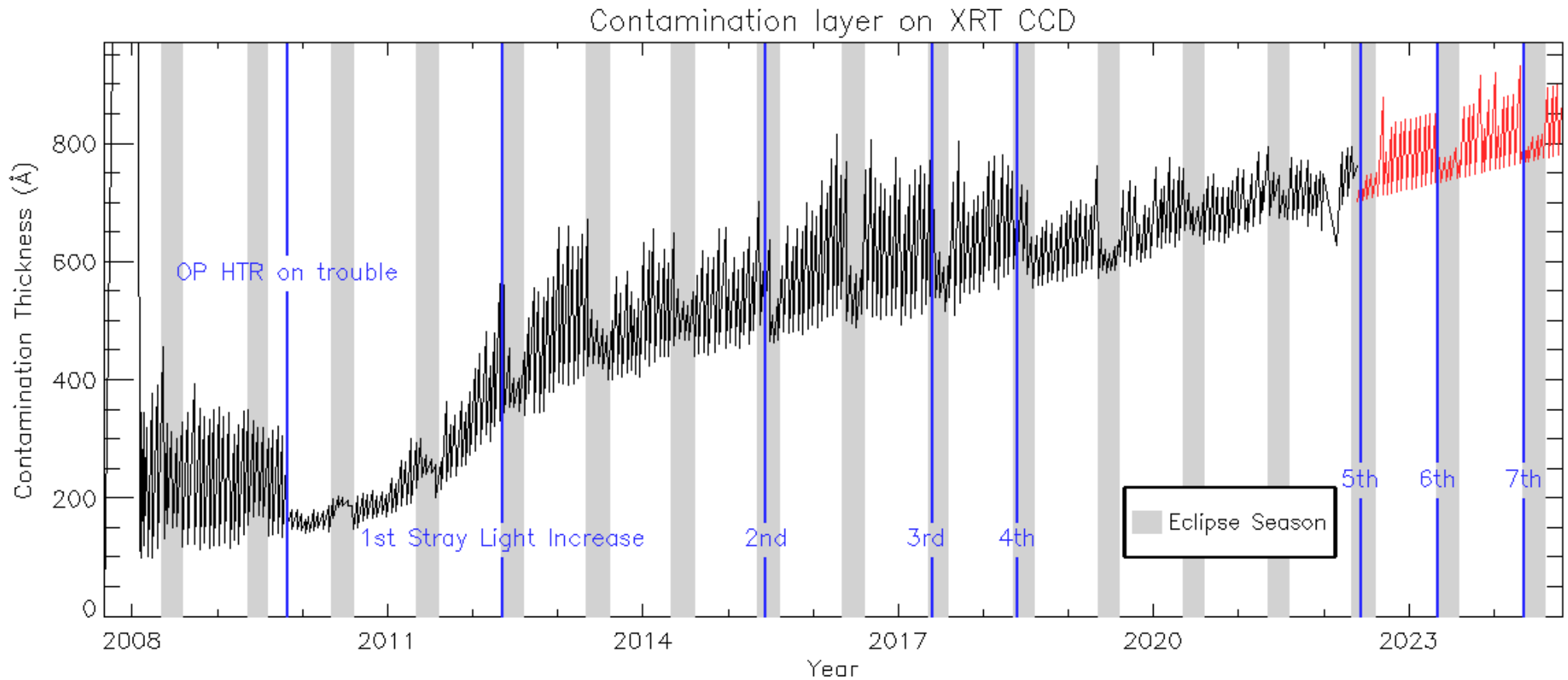


**Long term plots of
contamination thickness on CCD
and
roll angle**

K. Yoshimura (MSU)

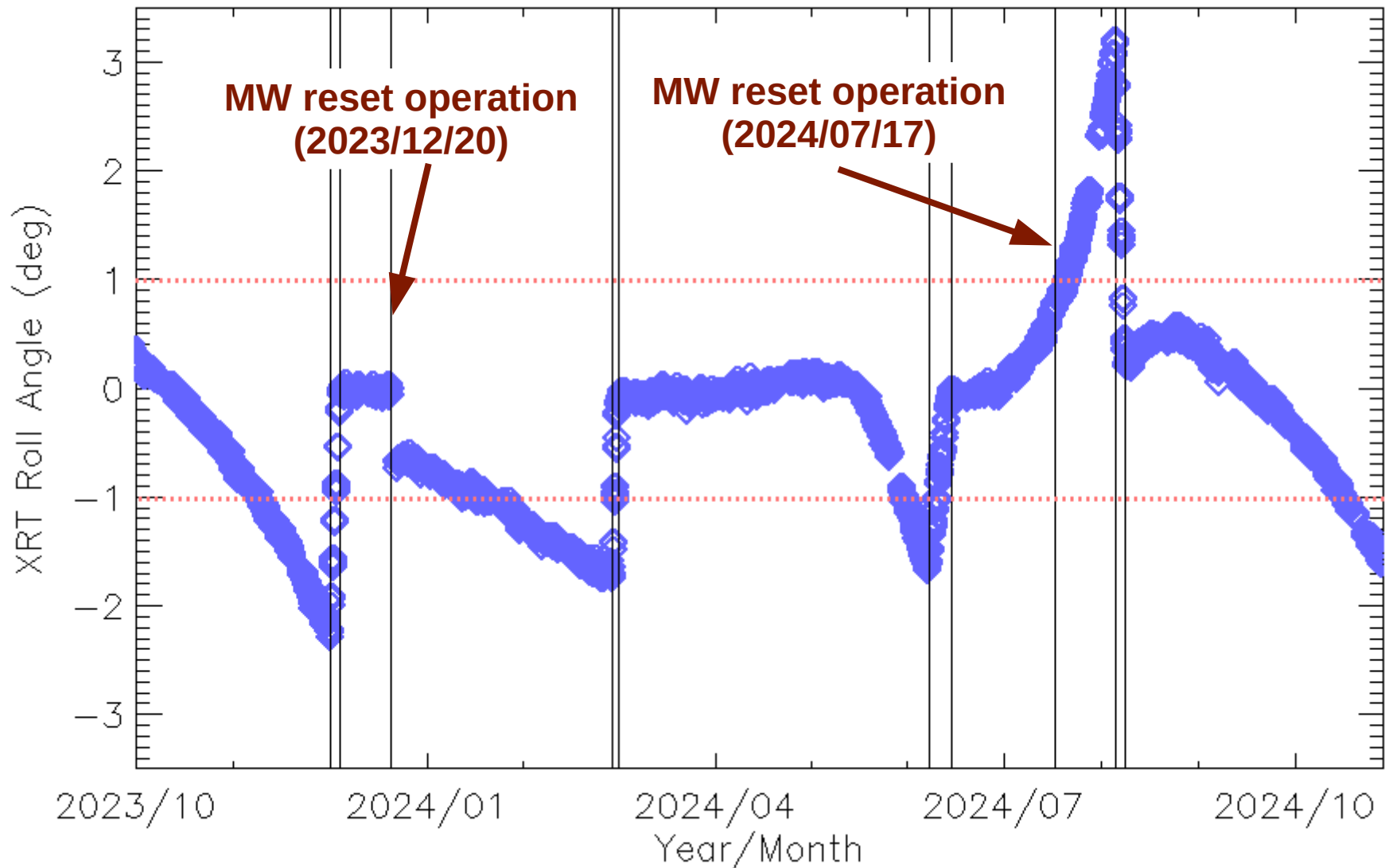
2024/10/29 XRT Calibration Meeting

Long term plot of contamination thickness (2007/09 – 2024/10)



Black line: measured values
Red line: extrapolated values

Long term plot of roll angle of XRT (2023/10 – 2024/10)



Vertical black lines show time of drift rate change operation

No anomaly